

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	258908	(382/128,129,130,131,132,133,134).CCLS. or (("600") or ("378") or ("250") or ("128")).CLAS.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/06 15:23
L2	547	1 and sag	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/06 16:08
L3	41	2 and ((align\$4 or adjust\$4) near4 (imag\$4))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/06 16:08
L4	23	3 and compensat\$4	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/06 15:29
L5	1	4 and (slice near4 image)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/06 15:29
L6	3	3 and (slice near4 image)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/06 15:41
L7	2	("5995581").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/06 15:41
L8	2	7 and position\$4	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/06 16:08

L9	1	8 and (slice near4 image)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/06 15:41
L10	0	("9and(calculat\$4ormeasur\$4orcom put\$4)").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/06 15:42
L11	1	9 and (calculat\$4 or comput\$4 or measur\$4)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/06 16:08
L12	0	11 and sag	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/06 15:42
L13	35	sag and (slice near4 imag\$4)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/06 16:16
L14	22	1 and 13	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/06 16:04
L15	7	14 and ((align\$4 or adjust\$4) near4 (imag\$4))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/06 16:46
L16	5	15 and (calculat\$4 or comput\$4 or measur\$4)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/06 16:17

L17	5	16 and sag	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/06 16:08
L18	5	17 and position\$4	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/06 16:17
L19	5	18 and (slice)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/06 16:09
L20	445	(swag or bend\$4 or sag) and (slice near4 imag\$4)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/06 16:23
L21	231	1 and 20	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/06 16:17
L22	59	21 and ((align\$4 or adjust\$4) near4 (imag\$4))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/06 16:17
L23	56	22 and (calculat\$4 or comput\$4 or measur\$4)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/06 16:17
L24	56	23 and position\$4	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/06 16:18

L25	47	24 and (accumulat\$4 or collect\$4)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/06 16:18
L26	4	((swag or bend\$4 or sag) near4 (correct\$4)) and (slice near4 imag\$4)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/06 16:28
L27	2	26 and bend\$4	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/06 16:29
L28	2	27 and tabl\$4	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/06 16:29
L29	2	28 and stor\$4	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/06 16:30
L30	0	29 and (acquair\$4 near4 imag\$4)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/06 16:30
L31	1	29 and (acquir\$4 near4 imag\$4)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/06 16:31
L32	0	31 and (imag\$4 near4 position)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/06 16:31

L33	1	31 and (imag\$4 near4 position\$4)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/06 16:38
L34	1	33 and stor\$4	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/06 16:46
L35	1	34 and adjustment\$4	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/06 16:47
L36	0	35 and ((align\$4 or adjust\$4) near4 (imag\$4))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/02/06 16:46

[IEEE HOME](#) | [SEARCH IEEE](#) | [SHOP](#) | [WEB ACCOUNT](#) | [CONTACT IEEE](#)[Membership](#) [Publications/Services](#) [Standards](#) [Conferences](#) [Careers/Jobs](#)**IEEE Xplore®**
RELEASE 1.5Welcome
United States Patent and Trademark Office[Help](#) [FAQ](#) [Terms](#) [IEEE Peer Review](#)[Quick Links](#)» [See](#)**Welcome to IEEE Xplore®**

- ☐ Home
- ☐ What Can I Access?
- ☐ Log-out

Tables of Contents

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

Search

- ☐ By Author
- ☐ Basic
- ☐ Advanced

Member Services

- ☐ Join IEEE
- ☐ Establish IEEE Web Account
- ☐ Access the IEEE Member Digital Library

[Print Format](#)

Your search matched 1 of 989552 documents.

A maximum of 1 results are displayed, 15 to a page, sorted by **Relevance** in descending order.

You may refine your search by editing the current search expression or entering a new one the text box.

Then click **Search Again**.**Results:**Journal or Magazine = **JNL** Conference = **CNF** Standard = **STD****1 Prediction of distribution system disturbances***Schwartzberg, J.W.; Nwankpa, C.O.; Fischl, R.; Sundaram, A.;*

Power Electronics Specialists Conference, PESC '94 Record., 25th Annual IEEE , June 1994

Page(s): 1077 -1082 vol.2

[\[Abstract\]](#) [\[PDF Full-Text \(340 KB\)\]](#) **IEEE CNF**

[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#)
[Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Alerting](#)
[No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Copyright © 2003 IEEE — All rights reserved

- ☐ Home
- ☐ What Can I Access?
- ☐ Log-out

Tables of Contents

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

Search

- ☐ By Author
- ☐ Basic
- ☐ Advanced

Member Services

- ☐ Join IEEE
- ☐ Establish IEEE Web Account
- ☐ Access the IEEE Member Digital Library

 [Print Format](#)

Design and implementation of a series voltage sag compensator under practical utility conditions

Po-Tai Cheng [Chian-Chung Huang](#) [Chun-Chiang Pan](#) [Bhattacharya, S.](#)

Dept. of Electr. Eng., Nat. Tsing Hua Univ., Hsin-Chu, Taiwan;

This paper appears in: Industry Applications, IEEE Transactions on

Publication Date: May-June 2003

On page(s): 844- 853

Volume: 39, Issue: 3

ISSN: 0093-9994

INSPEC Accession Number: 7648259

Abstract:

Voltage sags have become one of the most important power quality concerns recent years. According to survey results across the US, voltage sags and short duration power outages account for 92% of power quality problems encountered by industrial customers. Voltage sags often cause undervoltage faults in various sensitive loads and subsequently interrupt the manufacturing processes. Such interruptions often inflict severe losses for industries. In Taiwan, ROC, most high-tech manufacturers use uninterruptible power supplies to avoid interruptions, but the cost effectiveness of such an approach remains unclear. As the utility grid continues to improve the reliability of electric power, the inverter-based voltage sag compensator has become a viable solution to prevent production interruptions resulting from voltage sags. The existing sag compensation systems accomplish a fast response within a small fraction of a fundamental cycle by tracking the line voltages closely, and switch on the compensator whenever the voltage waveform deviates from the normal values. However, the utility voltages often contain transient spikes with amplitudes up to 200% resulting from switching of power factor-correction capacitors, circuit breakers switchings, lightning strikes, and so on. Such transient disturbances may trigger the sag compensator into operation if its controller is very sensitive. The switching frequency of the sag compensator inverter is inadequate to compensate the narrow pulses of voltage spikes. Furthermore, the power semiconductor devices (like insulated gate bipolar transistors) of the inverter may also be damaged due to overvoltage by the spikes. In this paper, a brief overview of power quality issues of a high-tech industry in Taiwan is provided to validate the need for ride-through technologies. A synchronous-reference-frame-based controller for the inverter-based voltage compensator is also presented. A sag detection mechanism is included in the controller for correct and prompt identification of voltage sags. Disturbances like voltage spikes are attenuated to avoid any false triggering of the compensator. The overall system responds to voltage sags and restores the voltage back to balance.

1.0 pu for critical loads within one-eighth to one-fourth of a cycle, which meets the requirement of industry standards like the SEMI-F47 standard. Simulation and laboratory test results are presented to verify the functionality of the proposed system.

Index Terms:

[circuit breakers](#) [compensation](#) [invertors](#) [power capacitors](#) [power factor correction](#) [power supply quality](#) [power system faults](#) [SEMI-F47 standard](#) [Taiwan](#) [circuit breakers switching](#) [false triggering avoidance](#) [high-tech manufacturers](#) [industrial customers](#) [insulated gate bipolar transistors](#) [inverter-based voltage sag compensator](#) [lightning strikes](#) [line voltage tracking](#) [manufacturing processes interruption](#) [power quality problems](#) [power semiconductor devices](#) [power-factor-correction capacitors](#) [ride-through technologies](#) [sag compensator](#) [sag compensator inverter](#) [sag detection mechanism](#) [sensitive loads](#) [series voltage sag compensator](#) [short-duration power outages](#) [switching frequency](#) [synchronous-reference frame-based controller](#) [transient disturbances](#) [transient spikes](#) [undervoltage faults](#) [uninterruptible power supplies](#) [utility conditions](#) [voltage spikes](#) [voltage waveforms](#)

Documents that cite this document

Select link to view other documents in the database that cite this one.

Reference list:

1. M. F. McGranaghan, D. R. Mueller, and M. J. Samotyj, "Voltage sags in industrial systems," *IEEE Trans. Ind. Applicat.*, vol. 29, pp. 397-403, Mar./Apr. 1993.
[Abstract] [PDF Full-Text (560KB)]
2. T. S. Chen and A. Liu, *Switching transient analysis of static power capacitor in the utility distribution system* Taipei, Taiwan, R.O.C.: Power Research Inst., T. Power Co., 1995.
3. W. K. Chang, *NSC 90-2218-E-194-046 analysis, simulation, and measurement of transients generated by switchable shunt capacitors in a power system* Taipei, Taiwan, R.O.C.: Nat. Science Council, 2002.
4. W. Y. Huang, *Switching surge and ferroresonance analyses for 161 kV system phase-III development region of Hsinchu Science Park*, M.S. thesis Hsin-Chu, Taiwan, R.O.C.: Nat. Tsing Hua Univ., June 2002.
5. T. E. Grebe, "Applications of distribution system capacitor banks and their impact on power quality," *IEEE Trans. Ind. Applicat.*, vol. 32, pp. 714-719, May/June 1996.
[Abstract] [PDF Full-Text (520KB)]
6. M. F. McGranaghan, T. E. Grebe, G. Hensley, T. Singh, and M. Samotyj, "Impact of utility switched capacitors on customer systems," *IEEE Trans. Power Delivery*, vol. 6, pp. 1623-1628, Oct. 1991.
[Abstract] [PDF Full-Text (444KB)]
7. V. E. Wagner, J. P. Staniak, and T. L. Orloff, "Utility capacitor switching and adjustable-speed drives," *IEEE Trans. Ind. Applicat.*, vol. 27, pp. 645-651, July/Aug. 1991.
[Abstract] [PDF Full-Text (652KB)]
8. T. A. Bellei, R. P. O'Leary, and E. H. Camm, "Evaluating capacitor-switching devices for preventing nuisance tripping of adjustable-speed drives due to voltage magnification," *IEEE Trans. Power Delivery*, vol. 11, pp. 1373-1378, July 1996.

[\[Abstract\]](#) [\[PDF Full-Text \(736KB\)\]](#)

9. A. A. Girgis, C. M. Fallon, J. C. P. Rubino, and R. C. Catoe, "Harmonics and transient overvoltages due to capacitor switching," *IEEE Trans. Ind. Applicat.*, 29, pp. 1184-1188, Nov./Dec. 1993.

[\[Abstract\]](#) [\[PDF Full-Text \(380KB\)\]](#)

10. *SEMI F47-0200 Specifications for semiconductor processing equipment voltage immunity* Mountain View, CA: Semiconductor Equipment and Materials International, 2000.

11. *ITI (CBEMA) curve application notes* Washington, DC: Information Technology Industry Council, 2000.

12. S. W. Middlekauff, "Field experience with a series compensation device," *PES Summer Meeting* San Diego, CA, 1998.

[\[Buy Via Ask*IEEE\]](#)

13. S. W. Middlekauff and E. R. Collins Jr, "System and customer impact: considerations for series custom power devices," *IEEE Trans. Power Delivery*, 13, pp. 278-282, Jan. 1998.

[\[Abstract\]](#) [\[PDF Full-Text \(500KB\)\]](#)

14. K. Chan and A. Kara, "Voltage sags mitigation with an integrated gate commutated thyristor based dynamic voltage restorer," *Proc. IEEE Int. Conf. Harmonics and Quality of Power*, 1998, pp. 561-565.

[\[Abstract\]](#) [\[PDF Full-Text \(384KB\)\]](#)

15. A. Kara, D. Amhof, P. Dahler, and H. Gruning, "Power supply quality improvement with a dynamic voltage restorer (DVR)," *Proc. IEEE APEC'98*, 1998, pp. 986-993.

[\[Abstract\]](#) [\[PDF Full-Text \(508KB\)\]](#)

16. W. E. Brumsickle, R. S. Schneider, G. A. Luckjiff, D. M. Divan, and M. F. McGranaghan, "Dynamic sag correctors: cost effective industrial power line conditioning," *IEEE Trans. Ind. Applicat.*, vol. 37, pp. 212-217, Jan./Feb. 2001.

[\[Abstract\]](#) [\[PDF Full-Text \(196KB\)\]](#)

17. K. Haddad, G. Joos, and S. Chen, "Control algorithm for series static voltage regulators in faulted distribution systems," *Proc. IEEE PESC'99*, 1999, pp. 414-423.

[\[Abstract\]](#) [\[PDF Full-Text \(416KB\)\]](#)

18. A. Sannino and J. Svensson, "Static series compensator for voltage sag mitigation supplying nonlinear loads," *Proc. IEEE PES Winter Meeting*, 2002, pp. 1147-1152.

[\[Abstract\]](#) [\[PDF Full-Text \(459KB\)\]](#)

19. C. Zhan, V. K. Ramachandramurthy, A. Arulampalam, C. Fitzer, S. Kromli, M. Barnes, and N. Jenkins, "Dynamic voltage restorer based on voltage-space-pwm control," *IEEE Trans. Ind. Applicat.*, vol. 37, pp. 1855-1863, Nov./Dec. 2001.

[\[Abstract\]](#) [\[PDF Full-Text \(316KB\)\]](#)

20. T. S. Key, "Diagnosing power quality-related computer problems," *IEEE Trans. Ind. Applicat.*, vol. 15, pp. 381-393, July/Aug. 1979.

[\[Buy Via Ask*IEEE\]](#)

21. S. Bhattacharya, P. T.Cheng, and D.Divan, "Hybrid solutions for improving passive filter performance in high power applications," *IEEE Trans. Ind. Appl.* vol. 33, pp. 732-747, May/June 1997.

[\[Abstract\]](#) [\[PDF Full-Text \(452KB\)\]](#)

22. S. Bhattacharya, D.Divan, and B.Banerjee, "Synchronous frame harmonic isolator using active series filter," *Proc. EPE'91*, 1991, pp. 30-35.

[\[Buy Via Ask*IEEE\]](#)

23. *Workshop on Power Quality for the Semiconductor Fabrication Industry*, Electric Power Research Institute (EPRI), 1998.

24. J. W. Schwartzberg and R. W.De Doncker, "15 kV medium voltage static transfer switch," *Conf. Rec. IEEE-IAS Annu. Meeting: IEEE*, 1995, vol. 3, pp. 2520.

[\[Abstract\]](#) [\[PDF Full-Text \(368KB\)\]](#)

[SEARCH RESULTS](#) [\[PDF Full-Text \(815 KB\)\]](#) [NEXT](#) [DOWNLOAD CITATION](#)

[Home](#) | [Log-out](#) | [Journals](#) | [Conference Proceedings](#) | [Standards](#) | [Search by Author](#) | [Basic Search](#) | [Advanced Search](#) | [Join IEEE](#) | [Web Account](#) | [New this week](#) | [OPAC Linking Information](#) | [Your Feedback](#) | [Technical Support](#) | [Email Us](#) | [No Robots Please](#) | [Release Notes](#) | [IEEE Online Publications](#) | [Help](#) | [FAQ](#) | [Terms](#) | [Back to Top](#)

Copyright © 2003 IEEE — All rights reserved